

<b>Notice of References Cited</b>	Application/Control No. 09/914,744	Applicant(s)/Patent Under Reexamination YOSHIDA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Han et al., "Soft Magnetic Properties of Fe-(Si <sub>3</sub> N <sub>4</sub> , Al <sub>2</sub> O <sub>3</sub> ) Thin Films", IEEE Journal, Vol. 32, No. 5, pp. 4490-4501, 9/96.
	V	
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